

Edition 1.0 2013-12

INTERNATIONAL STANDARD

NORME INTERNATIONALE



Mechanical structures for electronic equipment - Tests for IEC 60917 and IEC 60297 – Part 5: Seismic tests for chassis, subracks and plug-in units

Structures mécaniques pour équipement électronique₃₇₇Essais pour la CEI 60917 et la CEI 60297 -)d51-5fc97a45f092/iec-61587-5-2013 Partie 5: Essais sismiques pour châssis, bacs et unités enfichables





THIS PUBLICATION IS COPYRIGHT PROTECTED

Copyright © 2013 IEC, Geneva, Switzerland

All rights reserved. Unless otherwise specified, no part of this publication may be reproduced or utilized in any form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from either IEC or IEC's member National Committee in the country of the requester. If you have any questions about IEC copyright or have an enquiry about obtaining additional rights to this publication, please contact the address below or your local IEC member National Committee for further information.

Droits de reproduction réservés. Sauf indication contraire, aucune partie de cette publication ne peut être reproduite ni utilisée sous quelque forme que ce soit et par aucun procédé, électronique ou mécanique, y compris la photocopie et les microfilms, sans l'accord écrit de la CEI ou du Comité national de la CEI du pays du demandeur. Si vous avez des questions sur le copyright de la CEI ou si vous désirez obtenir des droits supplémentaires sur cette publication, utilisez les coordonnées ci-après ou contactez le Comité national de la CEI de votre pays de résidence.

IEC Central Office	Tel.: +41 22 919 02 11
rue de Varembé	Fax: +41 22 919 03 00
CH-1211 Geneva 20	info@iec.ch
Switzerland	www.iec.ch

About the IEC

The International Electrotechnical Commission (IEC) is the leading global organization that prepares and publishes International Standards for all electrical, electronic and related technologies.

About IEC publications

The technical content of IEC publications is kept under constant review by the IEC. Please make sure that you have the latest edition, a corrigenda or an amendment might have been published.

Useful links:

IEC publications search - www.iec.ch/searchpub

The advanced search enables you to find IES publications ICS. The world's leading online dictionary of electronic and by a variety of criteria (reference number, text, technical committee,...). It also gives information on projects, replaced Iand61587-5;additional languages. Also known as the International withdrawn publications.

IEC Just Published - webstore.iec.ch/justpublished fc97a45f092/iec-customer Service Centre - webstore.iec.ch/csc

Stay up to date on all new IEC publications. Just Published details all new publications released. Available on-line and also once a month by email.

If you wish to give us your feedback on this publication or need further assistance, please contact the Customer Service Centre: csc@iec.ch.

A propos de la CEI

La Commission Electrotechnique Internationale (CEI) est la première organisation mondiale qui élabore et publie des Normes internationales pour tout ce qui a trait à l'électricité, à l'électronique et aux technologies apparentées.

A propos des publications CEI

Le contenu technique des publications de la CEI est constamment revu. Veuillez vous assurer que vous possédez l'édition la plus récente, un corrigendum ou amendement peut avoir été publié.

Liens utiles:

Recherche de publications CEI - www.iec.ch/searchpub

La recherche avancée vous permet de trouver des publications CEI en utilisant différents critères (numéro de référence, texte, comité d'études,...).

Elle donne aussi des informations sur les projets et les publications remplacées ou retirées.

Just Published CEI - webstore.iec.ch/justpublished

Restez informé sur les nouvelles publications de la CEI. Just Published détaille les nouvelles publications parues. Disponible en ligne et aussi une fois par mois par email.

Electropedia - www.electropedia.org

Le premier dictionnaire en ligne au monde de termes électroniques et électriques. Il contient plus de 30 000 termes et définitions en anglais et en français, ainsi que les termes équivalents dans les langues additionnelles. Egalement appelé Vocabulaire Electrotechnique International (VEI) en ligne.

Service Clients - webstore.iec.ch/csc

Si vous désirez nous donner des commentaires sur cette publication ou si vous avez des questions contactez-nous: csc@iec.ch.



Edition 1.0 2013-12

INTERNATIONAL STANDARD

NORME INTERNATIONALE



Mechanical structures for electronic equipment - Tests for VEC 60917 and IEC 60297 – (standards.iteh.ai) Part 5: Seismic tests for chassis, subracks and plug-in units

IEC 61587-5:2013 Structures mécaniques pour équipement électronique 3-7 Essais pour la CEI 60917 et la CEI 60297 -451-5fc97a45f092/iec-61587-5-2013 Partie 5: Essais sismiques pour châssis, bacs et unités enfichables

INTERNATIONAL ELECTROTECHNICAL COMMISSION

COMMISSION ELECTROTECHNIQUE INTERNATIONALE

PRICE CODE CODE PRIX



ICS 31.240

ISBN 978-2-8322-1300-1

Warning! Make sure that you obtained this publication from an authorized distributor. Attention! Veuillez vous assurer que vous avez obtenu cette publication via un distributeur agréé.

 Registered trademark of the International Electrotechnical Commission Marque déposée de la Commission Electrotechnique Internationale

CONTENTS

FOF	REWORD	D	4		
INTE	NTRODUCTION				
1	Scope a	and object	7		
2	Normati	ive references	7		
3	Terms and definitions				
4	Equipme	ent test categories	8		
5		aveform and acceleration condition			
	5.1	General			
	5.2	General conditions			
	5.3	Single-axis acceleration			
	5.4	Tri-axial acceleration			
	5.5	Specimen monitoring			
	5.6	Seismic simulation			
6	Test set	tup and parts to be monitored	. 13		
	6.1	General	. 13		
	6.2	Category A - Plug-in-units	.13		
		Category A – Plug in units IDA RD PREVIEW 6.2.1 General	. 13		
		6.2.2 Plug-in (units mulated load t.e.h.ai)	.13		
		6.2.3 Plug-in unit test setup onto the test fixture			
		6.2.4 Plug-in unit test fixture setup to the vibration table	.17		
		6.2.5 https://lugdinduinip.m/eethanicarlapa/tist/uhbl43tes?327-4889-	. 18		
		6.2.6 Vibration response monitoring	. 18		
		6.2.7 Plug-in unit measurements			
		6.2.8 Test sequence	. 19		
		6.2.9 Plug-in unit electrical parts test (free and fixed connector)	.19		
		6.2.10 Acceptance criteria	. 19		
	6.3	Category B – Chassis or subracks	. 19		
		6.3.1 General	. 19		
		6.3.2 Chassis or subrack simulated load	.20		
		6.3.3 Chassis or subrack test setup onto the vibration table	.21		
		6.3.4 Chassis or subrack mechanical parts under test	.21		
		6.3.5 Vibration response monitoring	.21		
		6.3.6 Chassis or subrack measurements	. 22		
		6.3.7 Test sequence	. 22		
		6.3.8 Acceptance criteria	. 22		
Ann	ex A (info	formative) Example of test setup reporting	.23		
	A.1	Subrack test setup reporting	.23		
	A.2	Plug-in unit test setup reporting	.23		
Bibli	Bibliography24				

Figure 1 – RRS for the test wave (single-axis acceleration)(damping ratio 2,0 %)	10
Figure 2 – Time history of the test wave (single-axis acceleration)	10
Figure 3 – RRS for the test wave (tri-axial acceleration)(damping ratio 3 %)	11
Figure 4 – Time history of the test wave for each axis (tri-axial acceleration)	12

Figure 5 – Plug-in unit intended use A load distribution (discrete)	14
Figure 6 – Plug-in unit intended use B load distribution (compact)	15
Figure 7 – Plug-in unit test setup – Subrack	16
Figure 8 – Plug-in unit test setup – Chassis with integrated subrack	17
Figure 9 – Block diagram of the plug-in unit test setup	
Figure 10 – Chassis or subrack test setup	20
Figure 11 – Block diagram of the chassis or subrack test setup	21

iTeh STANDARD PREVIEW (standards.iteh.ai)

<u>IEC 61587-5:2013</u> https://standards.iteh.ai/catalog/standards/sist/60b1434d-2327-4889-9d51-5fc97a45f092/iec-61587-5-2013 - 4 -

INTERNATIONAL ELECTROTECHNICAL COMMISSION

MECHANICAL STRUCTURES FOR ELECTRONIC EQUIPMENT – TESTS FOR IEC 60917 AND IEC 60297 –

Part 5: Seismic tests for chassis, subracks and plug-in units

FOREWORD

- 1) The International Electrotechnical Commission (IEC) is a worldwide organization for standardization comprising all national electrotechnical committees (IEC National Committees). The object of IEC is to promote international co-operation on all questions concerning standardization in the electrical and electronic fields. To this end and in addition to other activities, IEC publishes International Standards, Technical Specifications, Technical Reports, Publicly Available Specifications (PAS) and Guides (hereafter referred to as "IEC Publication(s)"). Their preparation is entrusted to technical committees; any IEC National Committee interested in the subject dealt with may participate in this preparatory work. International, governmental and non-governmental organizations liaising with the IEC also participate in this preparation. IEC collaborates closely with the International Organization for Standardization (ISO) in accordance with conditions determined by agreement between the two organizations.
- The formal decisions or agreements of IEC on technical matters express, as nearly as possible, an international consensus of opinion on the relevant subjects since each technical committee has representation from all interested IEC National Committees.
- 3) IEC Publications have the form of recommendations for international use and are accepted by IEC National Committees in that sense. While all reasonable efforts are made to ensure that the technical content of IEC Publications is accurate, IEC cannot be held responsible for the way in which they are used or for any misinterpretation by any end user. (Standards.iten.al)
- 4) In order to promote international uniformity, IEC National Committees undertake to apply IEC Publications transparently to the maximum extent possible in their national and regional publications. Any divergence between any IEC Publication and the corresponding national or regional publication shall be clearly indicated in the latter. https://standards.iteh.ai/catalog/standards/sist/60b1434d-2327-4889-
- 5) IEC itself does not provide any attestation of conformity. Independent certification bodies provide conformity assessment services and, in some areas, access to IEC marks of conformity. IEC is not responsible for any services carried out by independent certification bodies.
- 6) All users should ensure that they have the latest edition of this publication.
- 7) No liability shall attach to IEC or its directors, employees, servants or agents including individual experts and members of its technical committees and IEC National Committees for any personal injury, property damage or other damage of any nature whatsoever, whether direct or indirect, or for costs (including legal fees) and expenses arising out of the publication, use of, or reliance upon, this IEC Publication or any other IEC Publications.
- 8) Attention is drawn to the Normative references cited in this publication. Use of the referenced publications is indispensable for the correct application of this publication.
- 9) Attention is drawn to the possibility that some of the elements of this IEC Publication may be the subject of patent rights. IEC shall not be held responsible for identifying any or all such patent rights.

International Standard IEC 61587-5 has been prepared by subcommittee 48D: Mechanical structures for electronic equipment, of IEC technical committee 48: Electromechanical components and mechanical structures for electronic equipment.

The text of this standard is based on the following documents:

FDIS	Report on voting
48D/549/FDIS	48D/553/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all parts of IEC 61587 series, under the general title *Mechanical structures for electronic equipment* – *Tests for IEC 60917 and IEC 60297*, can be found on the IEC website.

The committee has decided that the contents of this publication will remain unchanged until the stability date indicated on the IEC web site under "http://webstore.iec.ch" in the data related to the specific publication. At this date, the publication will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

IMPORTANT – The 'colour inside' logo on the cover page of this publication indicates that it contains colours which are considered to be useful for the correct understanding of its contents. Users should therefore print this document using a colour printer.

iTeh STANDARD PREVIEW (standards.iteh.ai)

<u>IEC 61587-5:2013</u> https://standards.iteh.ai/catalog/standards/sist/60b1434d-2327-4889-9d51-5fc97a45f092/iec-61587-5-2013

INTRODUCTION

This standard is based on IEC 61587-2: *Mechanical structures for electronic equipment* – *Tests for IEC 60917 and IEC 60297* – *Part 2: Seismic tests for cabinets and racks* and ATIS-0600329:2008:*Network Equipment* – *Earthquake Resistance*.

This standard sets forth test setups, performance requirements, and acceptance criteria for determining the robustness of chassis, subracks, and associated plug-in units according to the IEC 60297 and IEC 60917 series that may provide a level of survivability and preserve functionality during and after a seismic occurrence (an earthquake). This standard does not replace regional seismic system, installation standards, or specifications.

The intent of this standard is to provide a common methodology to perform and report seismic test conformance of chassis, subracks, and plug-in units according to the IEC 60297 and IEC 60917 series within a specified weight category. Mass distribution is based on the intended use. The terms "intended use" or "simulation of service condition" or "worst-case simulated configuration" are widely used in the telecom industry but also in the electronics industry.

Seismic ground motion occurs simultaneously and randomly in all directions. Single-axis or tri-axis tests may be selected to simulate the seismic environment for testing.

iTeh STANDARD PREVIEW (standards.iteh.ai)

<u>IEC 61587-5:2013</u> https://standards.iteh.ai/catalog/standards/sist/60b1434d-2327-4889-9d51-5fc97a45f092/iec-61587-5-2013

MECHANICAL STRUCTURES FOR ELECTRONIC EQUIPMENT – TESTS FOR IEC 60917 AND IEC 60297 –

Part 5: Seismic tests for chassis, subracks and plug-in units

1 Scope and object

This part of IEC 61587 specifies seismic test requirements for chassis, subracks, and plug-in units as defined in the IEC 60297 and IEC 60917 series. It applies in whole or in part, only to the mechanical structures of chassis, subracks, and plug-in units for electronic equipment, according to the IEC 60297 and IEC 60917 series, and does not apply to electronic components, equipment or systems within the mechanical structures.

NOTE Subracks may be an integral part of a chassis (often called in the industry a shelf or a crate).

The object of this standard is to establish a level of physical integrity of chassis, subracks, and plug-in units according to IEC 60297 and IEC 60917 series that may provide a level of survivability that will preserve functionality during and after a seismic occurrence. It is intended to provide the user with a high level of confidence in the selection of an equipment practice to meet such needs.

Since IEC 60297 and IEC 60917 series chassis, subracks, and plug-in units come in many sizes, weights and mechanical complexities, it is not possible to define a single minimum seismic test requirement for all weight categories. Therefore, overall mass categories are defined in this standard. However, the mass distribution inside a chassis and subrack is considered "application-specific" and herein defined as "intended use". https://standards.iteh.ai/catalog/standards/sist/60b1434d-2327-4889-

The single-axis or tri-axis acceleration for the seismic testing is selectable.

2 Normative references

The following documents, in whole or in part, are normatively referenced in this document and are indispensable for its application. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60068-2-6, Environmental testing – Part 2-6: Tests – Fc: Vibration (sinusoidal)

IEC 60068-2-47, Environmental testing – Part 2-47: Test – Mounting of specimens for vibration, impact and similar dynamic tests

IEC 60068-2-57, Environmental testing – Part 2-57: Tests – Test Ff: Vibration – Time-history and sine-beat method

IEC 60068-3-3, Environmental testing – Part 3-3: Guidance – Seismic test methods for equipment

IEC 60297 (all parts), Mechanical structures for electronic equipment – Dimensions of mechanical structures of the 482,6 mm (19 in) series

IEC 60297-3-101, Mechanical structures for electronic equipment – Dimensions of mechanical structures of the 482,6 mm (19 in) series – Part 3-101: Subracks and associated plug-in units

IEC 60512-2-1, Connectors for electronic equipment – Tests and measurements – Part 2-1: Electrical continuity and contact resistance tests – Test 2a: Contact resistance – Millivolt level method

IEC 60721-2-6, Classification of environmental conditions – Part 2: Environmental conditions appearing in nature. Earthquake vibration and shock

IEC 60917 (all parts), Modular order for the development of mechanical structures for electronic equipment practices

IEC 61587-1, Mechanical structures for electronic equipment – Tests for IEC 60917 and IEC 60297 series – Part 1: Environmental requirements, test set-up and safety aspects for cabinets, racks, subracks and chassis under indoor conditions

IEC 61587-2, Mechanical structures for electronic equipment – Tests for IEC 60917 and IEC 60297 – Part 2: Seismic tests for cabinets and racks

IEC 61587-3, Mechanical structures for electronic equipment – Tests for IEC 60917 and IEC 60297 – Part 3: Electromagnetic shielding performance tests for cabinets and subracks

3 Terms and definitions

For the purposes of this standard, the terms and definitions given in IEC 60068-2-6, IEC 60068-3-3, IEC 60068-2-47 and IEC 60068-2-57, apply as well as the following.

(standards.iteh.ai)

3.1

intended use

a method of use of the device under test that is the same as that recommended by the manufacturer for actual service of the device, and according to which the recommended configuration, bolt size, quantities, and torque values are used during testing

chassis

a mechanical structure according to IEC 60917-1. For the purpose of this standard a subrack may also be an integral part of the chassis

3.2

simulated load boards

simulated mass attached to plug-in units according to IEC 60917-1

3.3

simulated equipment

the total mass of a subrack, chassis with integrated subrack, chassis with components or plug-in unit fitted with simulated load

3.4

hot swap

managed plug-in units using electromechanical devices in the insertion and extraction process during actual service

4 Equipment test categories

Equipment (chassis, subracks, and plug-in units) being subjected to seismic testing shall be defined into one of the following mass categories. The test setup, the test method and acceptance criteria for the selected category shall be applied throughout the testing.

Category A1 – Plug-in unit simulated equipment \leq 1 kg

- Category A2 Plug-in unit simulated equipment > 1 kg and \leq 2 kg
- Category A3 Plug-in unit simulated equipment > 2 kg and \leq 5 kg
- Category A4 Plug-in unit simulated equipment > 5 kg and \leq 10 kg
- Category B1 Chassis or subrack simulated equipment ≤ 23 kg
- Category B2 Chassis or subrack simulated equipment \ge 23 kg and < 68 kg

Category B3 – Chassis or subrack simulated equipment \ge 68 kg and < 181 kg

5 Test waveform and acceleration condition

5.1 General

The parameters such as time history, zero period acceleration, damping ratio, and severities (frequency range, required response spectrum, acceleration per axis) have been derived from methods stated in IEC 60068-3-3, IEC 60068-2-57 and environment zone 4 as defined in IEC 60721-2-6.

5.2 General conditions

The tests shall be performed as follows:

- a) The test waveform for the seismic test shall be a synthesized waveform.
- b) The test shall be performed either with single-axis or tri-axis condition, as defined in this standard and reported accordingly.
- c) The duration of the strong part of the time history is defined from the time when the plot first reaches 25 % of the maximum value to the time when it falls for the last time to the 25 % level. 9d51-5fc97a45f092/iec-61587-5-2013
- d) The TRS (Test Response Spectrum) shall equal or exceed the RRS (Required Response Spectrum) as shown in Figure 1 (for single-axis) and Figure 3 (for tri-axis). The damping ratio of 3 % or 2 % is applied to evaluate the TRS and RRS, and is not applied to the frequency range less than 0,5 Hz and more than 50 Hz. The value of g (standard acceleration of gravity of the earth), is rounded up to the nearest whole number, that is 10 m/s².
- e) The test waveform shall satisfy the RRS.
- f) It is acceptable that the TRS is lower than the RRS typically found at the frequency range lower than half or larger than twice the 1st natural frequency, but shall not exceed 20 % of RRS.
- g) If the TRS does not satisfy the RRS with the limitation of the displacement of the vibration table, the TRS shall meet at the frequency range equal to or larger than 1 Hz.

5.3 Single-axis acceleration

- a) Accelerate each axis of the vibration table independently.
- b) The acceleration of the vibration table is measured during the test as described in 6.2.7 b) and 6.3.6 b).
- c) The duration of the strong part of the time history shall be equal to or more than 18 s.
- d) The zero period acceleration of the input test wave shall be 16 m/s², the RRS shall be according to Figure 1.
- e) The time history of the test wave is per Figure 2.

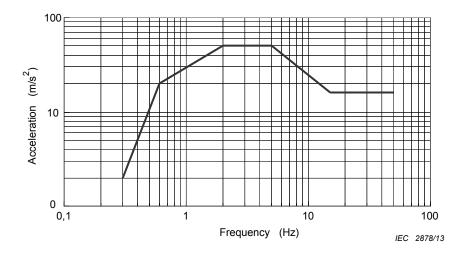


Figure 1 – RRS for the test wave (single-axis acceleration)(damping ratio 2,0 %)

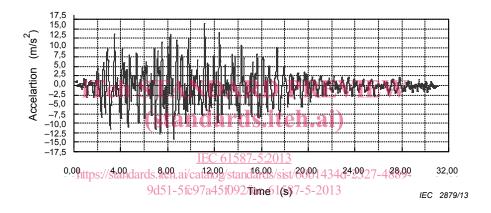


Figure 2 – Time history of the test wave (single-axis acceleration)

5.4 Tri-axial acceleration

- a) Accelerate the table along the three axes simultaneously.
- b) The acceleration of the individual axis differs from each other. The acceleration of the vibration table is measured during the test as described in 6.2.7 b) and 6.3.6 b).
- c) The duration of the strong part of the time history shall be equal to or more than 30 s.
- d) The required maximum acceleration (zero period acceleration) for the input test waveform shall be 12 m/s² for horizontal stroke and 6 m/s² for the up-and-down stroke, the RRS shall be according to Figure 3.
- e) Examples of the time history for each axis are shown in Figure 4.

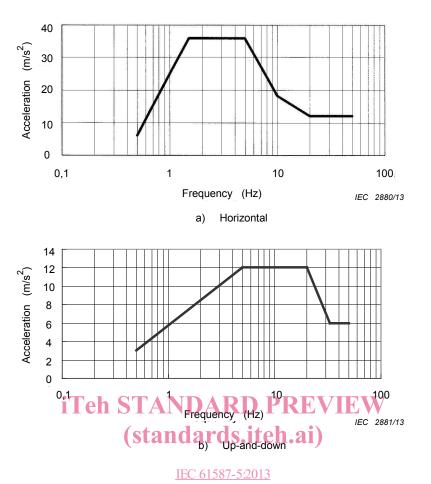


Figure 3 – RRS for the test wave (tri-axial acceleration)(damping ratio 3 %) 9d51-5fc97a45f092/iec-61587-5-2013

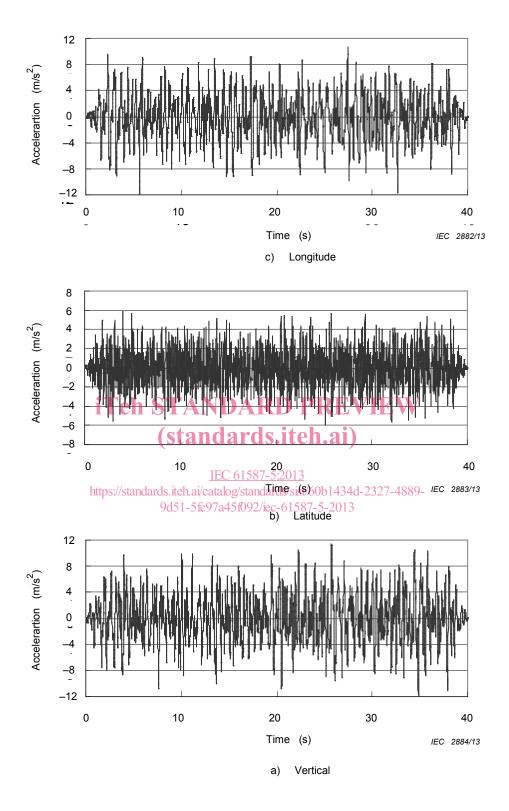


Figure 4 – Time history of the test wave for each axis (tri-axial acceleration)

5.5 Specimen monitoring

- a) The functionality of the chassis, subrack or plug-in unit (in accordance to IEC 61587-1, IEC 61587-3 and the intended use) shall be monitored before and after the seismic test, and optionally during the test.
- b) The chassis, subrack, or plug-in unit structural/mechanical condition shall be verified before and after testing.

c) For additional connector LLCR (Low Level Contact Resistance) testing (see 6.2.7 and 6.2.9) monitoring instrumentation shall respond at a rate that is adequate to detect intermittent malfunctions during testing. Intermittent malfunctioning time, if acceptable, is considered application specific.

5.6 Seismic simulation

- a) The chassis, subrack, or plug-in unit shall be subjected to vibration (resonance and seismic occurrence) tests along each of the three axes: longitudinal, transverse and vertical.
- b) The chassis, subrack or plug-in unit shall be subjected to the seismic simulation test by using the reference waveform.
- c) The resultant TRS shall be used to determine if the chassis, subrack or plug-in unit has been subjected to the adequate test level. The TRS shall meet or exceed the RRS over the frequency range of 1,0 Hz to 50 Hz.
- d) As an objective, the TRS should not exceed the RRS by more than 30 % in the amplified region of the RRS, from 3,0 Hz to 7,0 Hz, to prevent over testing of the chassis, subrack or plug-in unit.

6 Test setup and parts to be monitored

6.1 General

The seismic test of the chassis, subrack or plug-in unit shall be performed under "intended use" and simulated load condition. And intent is to be able to undertake the seismic test to assess the structural/mechanical integrity of a single chassis, a single subrack or a single plug-in unit. (standards.iten.al)

6.2 Category A – Plug-in units IEC 61587-5:2013

6.2.1 General https://standards.iteh.ai/catalog/standards/sist/60b1434d-2327-4889-9d51-5fc97a45f092/iec-61587-5-2013

Plug-in units according to IEC 60917 and IEC 60297 series interface with the subrack or chassis with integrated subrack. Plug-in units occupy a corresponding position (also called a "slot") in the subrack. To be able to conduct a seismic test for a single plug-in unit the corresponding subrack position (slot) and interface condition have to be repeated in the intended use subrack. The plug-in unit guide feature in the subrack shall reflect the intended use condition (i.e. guide width, guide depth, guide rigidity, guide material).

- The subrack or chassis shall be pre-qualified to Clause 4 of this standard and comply with Category B1, B2, or B3.
- The plug-in unit under test shall have the intended use free connector attached. The corresponding intended use fixed connector in the subrack or chassis with integrated subrack shall be attached to the subrack as per the intended use.
- The plug-in unit under test shall be inserted into the centre most slot of the subrack and retained with the intended use retention devices tightened to the recommended torque values. See Figures 7, 8 and 9.
- The subrack or chassis with integrated subrack test fixture shall be rigid, see Figures 7, 8 and 9. The test fixture shall be designed using the practices outlined in IEC 60068-2-47.

6.2.2 Plug-in unit simulated load

The simulated mass of a plug-in unit is defined in Clause 4, Category A1 to A4. This reflects the intended use of the plug-in unit consisting of the plug-in unit mass and the added simulated load.

• For the purpose of testing a plug-in unit shall be loaded with simulated load of suitable mass (with worst condition in mind) as shown in Figure 5 (intended use A, discrete